

<b>Notice of References Cited</b>	Application/Control No. 10/597,407	Applicant(s)/Patent Under Reexamination TAKUMAI, SUSUMU	
	Examiner DEVONA E. FAULK	Art Unit 2614	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0153391	07-2006	Hooley et al.	381/017
	B	US-			
	C	US-			
	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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